

## Publications scientifiques

Type d'Article	Nombre
Revues scientifiques avec comité de lecture	13
Conférences avec actes et comité de lecture	26
Colloques internationaux avec comité de lecture	11

### Revues scientifiques internationales avec comité de lecture

- F. Forero, J.-M. Galliere, M. Renovell, and V. Champac  
"Detectability Challenges of Bridge Defects in FinFET Based Logic Cells"  
Journal of Electronic Testing Theory and Applications (JETTA)  
February 2018  
DOI : 10.1007/s10836-018-5714-0
- A. Karel, M. Comte, J.-M. Galliere, F. Azais and M. Renovell  
"Resistive Bridging Defect Detection in Bulk, FDSOI and FinFET Technologies"  
Journal of Electronic Testing Theory and Applications (JETTA)  
Volume 33, Issue 4, pp. 515-527, August 2017  
ISSN : 0923-8174
- A. Karel, M. Comte, J.-M. Galliere, F. Azais and M. Renovell  
"Influence of Body-Biasing, Supply Voltage and Temperature on the detection of resistive short defects in FDSOI technology"  
IEEE Transactions on Nanotechnology,  
Volume 16, Issue 3, pp. 417-430, February 2017  
DOI : 10.1109/TNANO.2017.2664895
- J.-M. Galliere, F. Azais, M. Comte and M. Renovell  
"Testing for Gate Oxide Short Defects using the Detectability Interval Paradigm"  
De Gruyter - it - Information Technology  
Volume 56, Number 4, pp. 173-181, August 2014  
ISSN : 1611-2776
- F. Wrobel, J.-R. Vaillé, D. Pantel, L. Dilillo, J.-M. Galliere et al.,  
"A Silicon Diode-Based Detector for Investigations of Atmospheric Radiation"  
IEEE Transactions on Nuclear Science  
Volume 60, Issue 5, pp. 3603-3608, October 2013  
ISSN : 0018-9499
- F. Wrobel, J.-R. Vaillé, D. Pantel, L. Dilillo, J.-M. Galliere et al.,  
"Proton Flux Anisotropy in the Atmosphere: Experiment and Modeling"  
IEEE Transactions on Nuclear Science  
Volume 60, Issue 4, pp. 2386-2391, August 2013  
ISSN : 0018-9499
- P. Rech, J.-M. Galliere, P. Girard, A. Griffoni, J. Boch, F. Wrobel, F. Saigne, and L. Dilillo  
"Neutron-Induced Multiple Bit Upsets on Two Commercial SRAMs Under Dynamic-Stress"  
IEEE Transactions on Nuclear Science  
Volume 59, Issue 4, pp. 893-899, August 2012  
ISSN : 0018-9499

D. Pantel, J.-R. Vaillè, F. Wrobel, L. Dilillo, J.-M. Galliere, J.-L. Aufran et al.  
"Embedded Silicon Detector to Investigate the Natural Radiative Environment"  
Journal of Instrumentation  
Volume 7, pp. 1-11, May 2012  
**DOI** : 10.1088/1748-0221/7/05/P05007

P. Rech, J.-M. Galliere, P. Girard, F. Wrobel, F. Saigne and L. Dilillo  
"Impact of Resistive-Open Defects on SRAM Error Rate Induced by Alpha Particles and Neutrons"  
IEEE Transactions on Nuclear Science  
Volume 58, Issue 3, pp. 855-861, June 2011  
**ISSN** : 0018-9499

F. Wrobel, J.-R. Vaillè, D. Pantel, L. Dilillo, P. Rech, J.-M. Galliere et al.  
"Experimental Characterization of an Atmospheric Environment with a Stratospheric Balloon"  
IEEE Transaction on Nuclear Science  
Volume 58, Issue 3, pp. 945-951, June 2011  
**DOI** : 10.1109/TNS.2011.2136359

J.-M. Galliere, M. Renovell, F. Azaïs and Y. Bertrand  
"Delay Testing Viability of Gate Oxide Short Defects"  
Journal of Computer Science and Technology  
Volume 20, Number 2, pp.195-200, March 2005  
**ISSN** : 1000-9000

R. Bouchakour, J.-M. Portal, J.-M. Galliere, F. Azaïs, Y. Bertrand and M. Renovell  
"A Compact DC Model of Gate Oxide Short Defect"  
Microelectronic Engineering  
Volume 72, Number 1-4, pp. 140-148, April 2004  
**ISSN** : 0167-9317

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand  
"Modeling the Random Parameters Effects in a Non-Split Model of Gate Oxide Short"  
Journal of Electronic Testing Theory and Applications (JETTA)  
Volume 19, Number 4, pp. 377-386, August 2003  
**ISSN** : 0923-8174

### *Conférences internationales avec actes, comité de lecture*

M. Cozzi, J.-M. Galliere and P. Maurine  
"Thermal Scans for Detecting Hardware Trojans"  
9<sup>th</sup> IACR CAUSADE  
April 23-24, Singapore, 2018  
**ISBN** : to be published

A. Karel, F. Azais, M. Comte, J.-M. Galliere and M. Renovell  
"Impact of Process Variations on the Detectability of Resistive Short Defects: Comparative Analysis between 28nm Bulk and FDSOI"  
19<sup>th</sup> IEEE Latin American Test Symposium  
March 12-16, São Paulo, Brazil, 2018  
**ISBN** : to be published

A. Karel, M. Comte, J.-M. Galliere, F. Azais, M. Renovell and K. Singh  
"Comprehensive Study for Detection of Weak Resistive Open and Short Defects in FDSOI Technology"  
IEEE Computer Society Annual Symposium on VLSI (ISVLSI)  
July 3-5, Bochum, Germany, 2017  
**ISBN** : 978-1-5090-6762-6

A. Karel, M. Comte, J.-M. Galliere, F. Azais, M. Renovell and K. Singh  
"Detection of resistive open and short defects in FDSOI under delay-based test: Optimal VDD and body biasing conditions"  
22<sup>nd</sup> IEEE European Test Symposium  
May 22-26, Limassol, Cyprus, 2017  
**ISBN** : 978-1-5090-5457-2

- F. Forero, M. Renovell, J.-M. Galliere and V. Champac  
 "Analysis of Short Defects in FinFET Based Logic Cells"  
 18<sup>th</sup> IEEE Latin American Test Symposium  
 March 13-15, Bogota, Colombia, 2017  
 ISBN : 978-1-5386-0415-1
- A. Karel, M. Comte, J.-M. Galliere, F. Azais and M. Renovell  
 "Impact of VT and Body-biasing on resistive short detection in 28nm UTBB FDSOI-LVT and RVT configurations"  
 IEEE Computer Society Annual Symposium on VLSI (ISVLSI)  
 July 11-13, Pittsburgh, USA, 2016  
 ISBN : 978-1-4673-9038-5
- A. Karel, M. Comte, J.-M. Galliere, F. Azais and M. Renovell  
 "Comparative study of Bulk, FDSOI and FinFET technologies in presence of a resistive short defect"  
 17<sup>th</sup> IEEE Latin American Test Symposium  
 April 6-8, Foz do Iguaçu, Brazil, 2016  
 ISBN : 978-1-5090-1331-9
- R. Kheirallah, J.-M. Galliere, A. Todri-Sanial, N. Azemard and G. Ducharme  
 "Statistical Energy Study for 28nm FDSOI Devices"  
 IEEE EuroSime,  
 April 19-23, Budapest, Hungary, 2015  
 ISBN : 978-1-4799-9949-1
- D. Pantel, J.-R. Vaile, F. Wrobel, L. Dilillo, J.-M. Galliere, J.-L. Autran et al.  
 "A Silicon Diode Based Detector for Radiation Measurement in High Altitude Natural Environment"  
 IEEE (Nuclear Plasma Society) Real Time Conference, Berkeley, USA, 2012  
 ISBN : 978-1-4673-1082-6
- P. Rech, J.-M. Galliere, P. Girard, A. Griffoni, F. Wrobel, F. Saigné, and L. Dilillo  
 "Neutron-Induced Multiple Bit Upsets on Dynamically-Stressed Commercial SRAM Arrays"  
 12th IEEE European Conference on Radiation and its Effects on Components and Systems  
 September 19-23, Sevilla, Spain, 2011  
 ISBN : 978-1-4577-0585-4
- P. Rech, J.-M. Galliere, P. Girard, F. Wrobel, F. Saigné, and L. Dilillo  
 "Dynamic-Stress Neutrons Test of Commercial SRAMs"  
 IEEE Nuclear and Space Radiation Effects Conference,  
 July 25-29, Las Vegas, USA, 2011
- L. Dilillo, P. Rech, J.-M. Galliere, P. Girard, F. Wrobel and F. Saigne  
 "Neutron Detection in Atmospheric Environment through Static and Dynamic SRAM-Based Test Bench"  
 12<sup>th</sup> IEEE Latin American Test Workshop  
 March 27-30, Porto de Galinhas, Brazil, 2011  
 ISBN : 978-1-4577-1490-0
- J.-M. Galliere, P. Rech, P. Girard and L. Dilillo  
 "A Roaming Memory Test Bench for Detecting Particle- induced SEUs"  
 International Test Conference,  
 October 31 - November 5, Austin, USA, 2010  
 ISBN : 978-1-4244-7205-5
- J.-M. Galliere, P. Papet and L. Latorre  
 "A 2-D KLM Model for Disk-Shape Piezoelectric Transducers"  
 The Second International Conference on Advances in Circuits, Electronics and Micro-electronics  
 October 11-16, Sliema, Malta, 2009  
 ISBN: 978-0-7695-3832-7
- L. Dilillo, F. Wrobel, J.-M. Galliere and Frederic Saigne  
 "Neutron Detection through an SRAM-Based Test Bench", pp. 64-69  
 23rd IEEE International Workshop on Advances in Sensors and Interfaces,  
 June 25-26, Trani (Bari), Italy, 2009  
 ISBN: 978-1-4244-4708-4

- J.-M. Galliere, F. Azais, M. Renovell and L. Dilillo  
 "Influence of Gate Oxide Short Defects on the Stability of Minimal Sized SRAM Core-cell by Applying Non-Split Models"  
 IEEE Int. Conference Design & Technology of Integrated Systems  
 April 6-7, Cairo, Egypt, 2009  
 ISBN : 978-1-4244-4321-5
- J.-M. Galliere, P. Papet and L. Latorre  
 "A 2-D VHDL-AMS Model for Disk-Shape Piezoelectric Transducers"  
 IEEE Behavioral Modeling and Simulation Conference  
 September 25-26, San Jose, USA, 2008  
 ISBN : 978-1-4244-2896-0
- J.-M. Galliere, P. Papet and L. Latorre  
 "A Unified Electrical SPICE Model for Piezoelectric Transducers"  
 IEEE Behavioral Modeling and Simulation Conference  
 September 20-21, San Jose, USA, 2007  
 ISBN : 978-1-4244-1567-0
- I. Polian, S. Kundu, J.-M. Galliere, P. Engelke, M. Renovell and B. Becker  
 "Resistive Bridge Fault Model Evolution From Conventional to Ultra Deep Submicron Technologies"  
 23<sup>rd</sup> IEEE VLSI Test Symposium  
 May 1-5, Palm Spring, USA, 2005  
 ISBN : 0-7695-2314-5
- S. Bernardini, P. Masson and J.-M. Portal - L2MP  
 J.-M. Galliere and M. Renovell - LIRMM  
 "Impact of Gate Oxide Reduction Failure on Analog Application : Example of the Current Mirror"  
 5<sup>th</sup> IEEE Latin American Test Workshop, pp.12-17  
 March 8-10, Cartagena, Colombia, 2004  
 ISBN : 9-5833-5899-1
- M. Renovell, J.-M. Galliere, F. Azais and Y. Bertrand  
 "Delay Testing of MOS Transistor with Gate Oxide Short"  
 12<sup>th</sup> Asian Test Symposium,  
 November 17-19, Xi'an, China, 2003  
 ISBN : 0-7695-1951-2
- M. Renovell, J.-M. Galliere, F. Azais and Y. Bertrand  
 "A Non-Split Model for Realistic Gate Oxide Short in CMOS Technology"  
 Conference on Design of Circuits and Integrated Systems, pp. 197-204  
 November 19-22, Santander, Spain, 2002  
 ISBN : 8-4810-2311-6
- M. Renovell, J.-M. Galliere, F. Azais and Y. Bertrand  
 "Modeling Gate Oxide Short Defects in CMOS Minimum Transistors"  
 7<sup>th</sup> IEEE European Test Workshop, pp. 15-20  
 May 26-29, Corfu, Greece, 2002  
 ISBN : 0-7695-1715-3
- M. Renovell, J.-M. Galliere, F. Azais and Y. Bertrand  
 "Low Voltage Testing of Gate Oxide Short in CMOS Technology"  
 5<sup>th</sup> International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems  
 April 17-19, Brno, Czech Republic, 2002  
 ISBN : 8-0214-2094-4
- M. Renovell, J.-M. Galliere, F. Azais and Y. Bertrand  
 "Boolean and Current Detection of MOS Transistor with Gate Oxide Short"  
 International Test Conference, pp. 1039-1048  
 October 30 – November 1, Baltimore, USA, 2001  
 ISBN : 0-7803-7169-0

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand  
"Analysing the Characteristics of MOS Transistors in the Presence of Gate Oxide Short"  
4<sup>th</sup> International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems,  
April 18-20, Győr, Hungary, 2001  
ISBN : 9-6371-7516-4

Colloques internationaux avec comité de lecture

A. Karel, M. Comte, J.-M. Galliere, F. Azaïs and M. Renovell  
"Comparative study of FinFET and FDSOI nanometric technologies based on manufacturing defect testability"  
GDR: Groupement De Recherche Soc-SiP  
Nantes, France, 2016

F. Wrobel, J.-R. Vaillé, D. Pantel, L. Dilillo, J.-M. Galliere et al.  
"Proton Flux Anisotropy in the Atmosphere: Experiment and Modeling"  
13th IEEE European Conference on Radiation and its Effects on Components and Systems  
September 24-28, Biarritz, France, 2012

P. Rech, J.-M. Galliere, F. Wrobel, F. Saigné and L. Dilillo  
"Impact of Resistive-Open Defects on SRAM Error Rate Induced by Alpha Particles and Neutrons"  
11th European Conference on Radiation and its Effects on Components and Systems  
September 20-24, Langenfeld, Austria, 2010

F. Wrobel, J.-R. Vaillé, D. Pantel, L. Dilillo, P. Rech, J.-M. Galliere et al.  
"Experimental Characterization of Atmospheric Radiation Environment with Stratospheric Balloon"  
11th European Conference on Radiation and its Effects on Components and Systems  
September 20-24, Langenfeld, Austria, 2010

J.-M. Galliere and P. Papet  
"A 2-D Electrical Model for Disk-Shape Piezoelectric Transducers"  
XXII Conference on Design of Circuits and Integrated Systems  
November 21-23, Sevilla, Spain, 2007

R. Bouchakour and J.-M. Portal - L2MP  
J.-M. Galliere, F. Azaïs, Y. Bertrand and M. Renovell - LIRMM  
"A Compact DC Model of Gate Oxide Short Defect",  
Insulating Films on Semiconductors,  
June 18-20, Barcelona, Spain, 2003

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand - LIRMM  
J.M. Portal et R. Bouchakour - L2MP  
"An Embedded Gate Oxide Short Model for Efficient Electrical Simulation"  
9<sup>th</sup> Workshop IBERCHIP  
March 26-28, La Habana, Cuba, 2003

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand - LIRMM  
J.M. Portal et R. Bouchakour - L2MP  
"GOSMOS : A Gate Oxide Short Defect Embedded in a MOS Compact Model"  
4<sup>th</sup> IEEE Latin American Test Workshop, pp. 6-11  
February 16-19, Natal, Brazil, 2003

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand  
"Non-Linear and Non-Split Transistor MOS Model for Gate Oxide Short"  
IEEE International Workshop on Defect Based Testing, pp. 11-16  
April 28, Monterey, USA, 2002

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand  
"A Complete Analysis of the Voltage Behaviour of MOS Transistor with Gate Oxide Short"  
IEEE International Workshop on Defect Based Testing, pp. 5-10  
April 29, Los Angeles, USA, 2001

M. Renovell, J.-M. Galliere, F. Azaïs and Y. Bertrand  
"Electrical Analysis of Gate Oxide Short in MOS Technologies"  
2<sup>nd</sup> IEEE Latin American Test Workshop, pp.266-272

February 11-14, Cancun, Mexico, 2001

## Publications pédagogiques

Type d'Article	Nombre
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Conférences avec actes et comité de lecture	9
Colloques internationaux avec comité de lecture	2
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### Revue scientifique internationale avec comité de lecture et ISSN

J.-M. Galliere

"Programmable Analog Arrays, an answer for Control-Systems Practical Works"

WSEAS Transactions on Advances in Engineering Education

Volume 3, Issue 8, pp. 783-787, August 2006

ISSN : 1790-1979

### Conférences internationales avec actes, comité de lecture et ISBN

J.-M. Galliere and J. Boch

"A Toolkit to Demystify CMOS Active Pixel Sensors"

IEEE International Conference on Microelectronic Systems Education,

June 2-3, Austin, USA, 2013

ISBN: 978-1-4799-0139-5

J.-M. Galliere and L. Dillo

"Versatile March Test Generator for Hands-on Memory Testing Laboratory"

IEEE International Conference on Microelectronic Systems Education,

June 5-6, San Diego, USA, 2011

ISBN: 978-1-4577-0550-2

J.-M. Galliere and J. Boch

"A Mixed TCAD/Electrical Simulation Laboratory to Open up the Microelectronics Teaching" pp. 37-40

IEEE International Conference on Microelectronic Systems Education,

July 25-27, San Francisco, USA, 2009

ISBN: 978-1-4244-4406-9

J.-M. Galliere and J. Boch

"Mixed TCAD/Electrical Simulation Learning"

8<sup>th</sup> European Workshop on Microelectronics Education (EWME)

May 28-30, Budapest, Hungary, 2008

ISBN : 978-2-35500-007-2

J.-M. Galliere

"Programmable Analog Array in Control-Systems Laboratory"

IEEE Mediterranean Conference on Control and Automation

June 27-29, Athens, Greece, 2007

ISBN : 978-960-254-664-2

J.-M. Galliere and G. Cathebras

"Stream Manager, Easy CAD Tools Switching in Academic Context"

IEEE Conference on Microelectronic Systems Education

June 2-4, San Diego, USA, 2007

ISBN : 0-7695-2849-X

J.-M. Galliere  
"A Control-Systems FPAA Based Tutorial"  
2<sup>nd</sup> WSEAS International Conference on Educational Technologies, pp39-42  
October 16-18, Bucharest, Roumania, 2006  
ISBN : 960-8457-54-8

J.-M. Galliere and G. Cathebras  
"Stream Manager, an Answer to Academic Project Policy"  
IEEE Conference on Automation, Quality and Testing, Robotics, pp 127-129  
May 25-28, Cluj-Napoca, Roumania, 2006  
ISBN : 1-4244-0361-8

J.-M. Galliere  
"Extensive CMOS and Electrical Simulation Learning",  
6<sup>th</sup> European Workshop on Microelectronics Education (EWME),  
June 8-9, Stockholm, Sweden, 2006  
ISBN : 91-7178-402-0

### Colloques internationaux avec comité de lecture

J.-M. Galliere and L. Dilillo  
"Séquence pédagogique dédiée à l'apprentissage des techniques de test des mémoires"  
9e Colloque sur l'Enseignement des Technologies et des Sciences de l'Information et des Systèmes  
October 23-26, Trois Rivières, Canada, 2011

J.-M. Galliere and G. Cathebras  
"Stream Manager Facility in Microelectronics Projects",  
CDNLive! EMEA 2007  
May 14-16, Munich, Germany, 2007

### Colloques nationaux avec comité de lecture et ISBN

J.-M. Galliere and L. Dilillo  
"Banc de Test Programmable Dédié à l'Apprentissage des Techniques de Test des Mémoires"  
11<sup>èmes</sup> Journées Pédagogiques du CNFM  
Novembre 22-24, Saint-Malo, 2010  
ISBN : 2-9522395-3-3

J.-M. Galliere and J. Boch  
"Mise en Œuvre de la Simulation Mixte pour Décloisonner l'Enseignement de la Microélectronique"  
10<sup>èmes</sup> Journées Pédagogiques du CNFM  
Novembre 26-28, Saint-Malo, 2008  
ISBN : 2-9522395-2-5

J.-M. Galliere and G. Cathebras  
"Stream Manager : une Assistance à la Gestion des Projets Microélectroniques"  
9<sup>èmes</sup> Journées Pédagogiques du CNFM  
Novembre 22-24, Saint-Malo, 2006  
ISBN : 2-9522395-1-7